

Single N-channel MOSFET

KFK4A25019NL Datasheet

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1. GENERAL DESCRIPTION

Single N-channel MOSFET.

2. FEATURES

- Drain-source On-state Resistance: RDS(on) typ = $43 \text{ m}\Omega$ (VGS = 4.5 V)
- · CSP (Chip Size Package)
- Halogen-free / RoHS compliant (EU RoHS / UL-94 V-0 / MSL: Level 1)

3. MARKING SYMBOL: TB

4. PACKAGING

Embossed type (Thermo-compression sealing): 13,000 pcs / reel (standard)

5. ABSOLUTE MAXIMUM RATINGS Ta = 25 °C

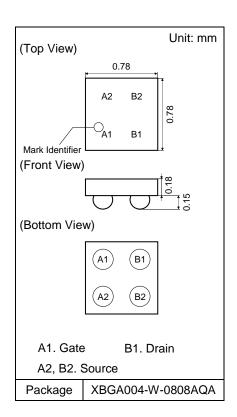
Parameter	Symbol	Rating	Unit		
Drain-source Voltage		VDS	25	V	
Gate-source Voltage		VGS	± 12	V	
	DC *1	ID1	2.7		
Drain Current	DC *2	ID2	4.2	Α	
	DC *3	ID3	5.4		
	Pulsed*4	IDp	27		
	DC *1	PD1	0.43		
Total Power Dissipation	DC *2	PD2	1.00	W	
	DC *3	PD3	1.65		
Operating Junction and Storage Temperature Range		Tj, Tstg	- 55 to + 150	°C	

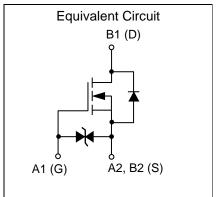
6. THERMAL CHARACTERISTICS Ta = 25 °C

Parameter	Symbol	Rating	Unit
	Rth1 *1	290	
Thermal Resistance (ch-a)	Rth2 *2	125	°C / W
	Rth3 *3	76	

Note *1 Mounted on FR4 board (25.4 mm x 25.4 mm x t1.0 mm). FR4 board partially covered with copper pad (65.5 mm² area, 36 µm thickness).

- *2 Mounted on FR4 board (25.4 mm x 25.4 mm x t1.0 mm). FR4 board fully covered with copper pad (616 mm² area, 36 μm thickness).
- $^{*}3$ Mounted on ceramic board (70 mm x 70 mm x t1.0 mm).
- *4 $t = 10 \ \mu s$, Duty Cycle $\leq 1 \%$.





Rev 1.00

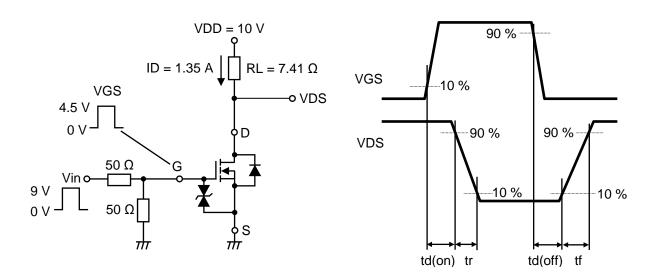


7. ELECTRICAL CHARACTERISTICS Ta = 25 °C ± 3 °C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit	
Drain-source Breakdown Voltage	VDSS	ID = 1 mA, VGS = 0 V	25			V	
Zero Gate Voltage Drain Current	IDSS	VDS = 25 V, VGS = 0 V			10	μA	
Cata aguras Logkago Current	IGSS	$VGS = \pm 8 \text{ V}, VDS = 0 \text{ V}$			± 1		
Gate-source Leakage Current	VGS = ± 5 V, VDS = 0 V				± 0.1	μA	
Gate-source Threshold Voltage	Vth	ID = 0.18 mA, VDS = 10 V	0.3	0.7	1.0	V	
	RDS(on)1	ID = 1.35 A, VGS = 4.5 V	28	43	56		
Drain course On state Registeres	RDS(on)2	ID = 1.35 A, VGS = 3.8 V	29	44	57		
Drain-source On-state Resistance	RDS(on)3	ID = 1.35 A, VGS = 3.1 V	31	47	66	mΩ	
	RDS(on)4	ID = 1.35 A, VGS = 2.5 V	35	53	74		
Body Diode Forward Voltage	VF(s-d)	IF = 1 A, VGS = 0 V		0.7	1.0	V	
Input Capacitance *1	Ciss	VDC 00 V VCC 0 V		200			
Output Capacitance *1	Coss	VDS = 20 V, VGS = 0 V f = 1 MHz		30		pF	
Reverse Transfer Capacitance *1	Crss			20			
Turn-on Delay Time *1, *2	td(on)	VDD = 10 V, VGS = 0 to 4.5 V		6			
Rise Time *1, *2	tr	ID = 1.35 A		6			
Turn-off Delay Time *1, *2	td(off)	VDD = 10 V, VGS = 4.5 to 0 V		28		ns	
Fall Time *1, *2	tf	ID = 1.35 A		11			
Total Gate Charge *1	Qg	VDD 40.V VCC 4.5.V		2.7			
Gate-source Charge *1	Qgs	VDD = 10 V, VGS = 4.5 V		0.6		nC	
Gate-drain Charge *1	Qgd	ID = 2.7 A		0.8			

Note Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors.

- *1 Guaranteed by design, not subject to production testing.
- *2 Measurement circuit for Turn-on Delay Time / Rise Time / Turn-off Delay Time / Fall Time.

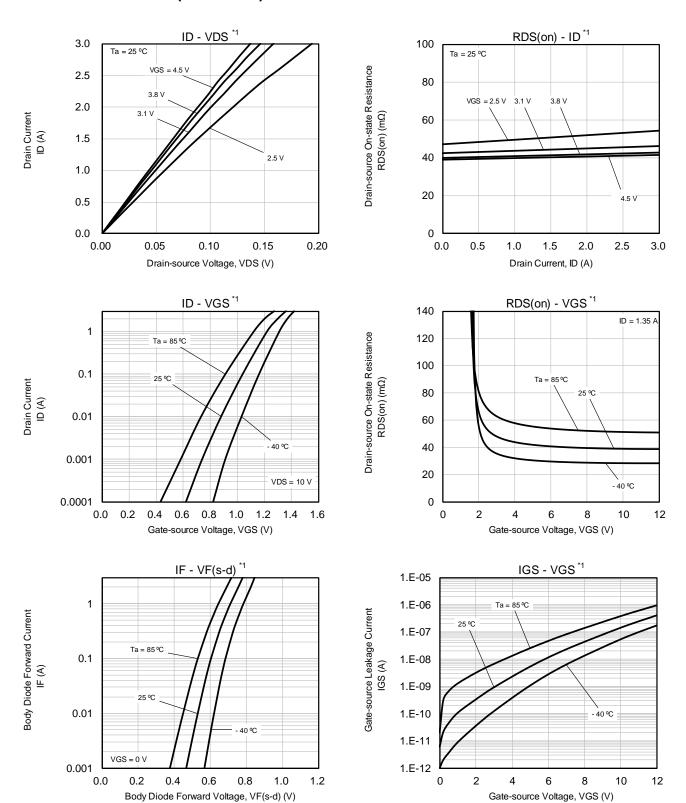


8. ELECTROSTATIC DISCHARGE CHARACTERISTIC Ta = 25 °C ± 3 °C

Standard	Test Type	Symbol	Conditions	Class	Value	Unit
AEC-Q101-001	Human Body Model	HBM	$C = 100 \text{ pF}, R = 1.5 \text{ k}\Omega$	H1C	> 1 to ≤ 2	kV

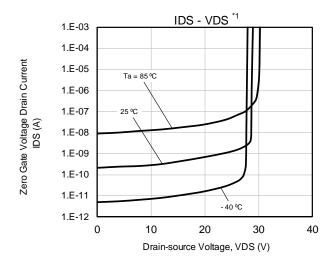


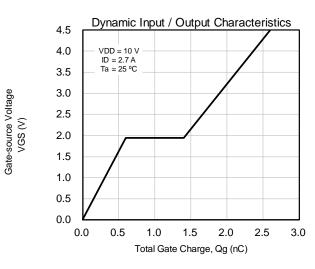
9. TECHNICAL DATA (Reference)

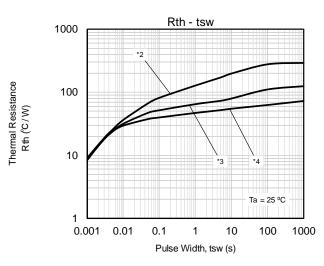


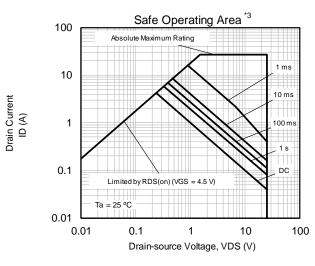


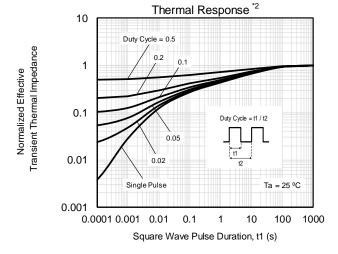
TECHNICAL DATA (Reference)











Note

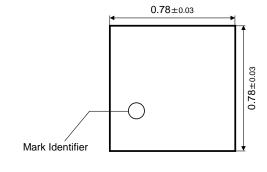
- *1 Pulse measurement.
- *2 Mounted on FR4 board (25.4 mm × 25.4 mm × t1.0 mm). FR4 board partially covered with copper pad (65.5 mm² area, 36 μm thickness).
- *3 Mounted on FR4 board (25.4 mm x 25.4 mm x t1.0 mm). FR4 board fully covered with copper pad (616 mm² area, 36 µm thickness).
- *4 Mounted on ceramic board (70 mm × 70 mm × t1.0 mm).



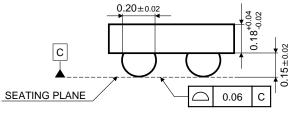
10. OUTLINE

(Top View)

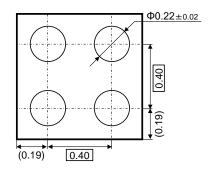




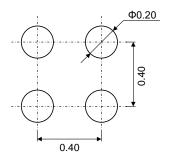
(Front View)



(Bottom View)



11. LAND*1 & STENCIL PATTERN (Reference)

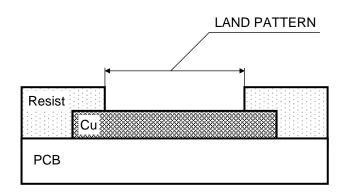


Unit: mm

Note *1 The definition of land pattern is referred to next page.



DEFINITION OF LAND PATTERN



Important notice:

Solder Mask Defined (SMD) pattern is strongly recommended for pad design.

Please check the information in the Nuvoton WL-CSP Application Notes about mounting process.



12. REVISION HISTORY

Date	Revision	Description
2022.8.26	1.00	1. Initially issued.



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